



## IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L DEKRA 17.0001	Issue No.:	2	Status:	Current
Supersedes:	<a href="#">IECQ-L DEKRA 17.0001 Issue 1</a>	Issue Date:	2017/11/27	Org Issue:	2011/11/27
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The organization, facilities and procedures have been assessed and found to comply with the applicable requirements for Independent Testing Laboratory organization approval, in support of the IECQ system, which is in accordance with the Basic Rules IECQ 01 and Rules of Procedure IECQ 03-6 "Independent Testing Laboratory Assessment Program Requirements" of the IEC Quality Assessment System for Electronic Components (IECQ) and applicable requirements of ISO/IEC 17025: 2005 for the testing of electronic components under the IECQ.

#### Scope:

**Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials**

See attached Schedule of Scope

-- Attached Schedule: IECQ-L DEKRA 17.0001-S Rev2.pdf --

Approved by Certification Body (CB): DEKRA Certification B.V.

Meander 1051  
Arnhem  
Netherlands

Authorized person:  
Ted Gaertner



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

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**Schedule of Scope to Certificate of Approval**  
**Independent Testing Laboratory**  
IECQ Certificate No.: IECQ-L DEKRA 17.0001  
CB Certificate No.: DEKRA-C10A

Schedule Number: IECQ-L DEKRA 17.0001-S    Rev No.: 2    Revision Date: 2017/11/27    Page 1 of 1

**1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials**

Description test	Standard	Remarks
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, including FIB (Focused Ion Beam), SEM (Scanning electron microscope)	MIL-STD-883 Method 2018.4 JESD22A121 JESD201	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, includes Electrical Analysis and Physical Analysis with Sample Preparation (Decap, X-section, etc)	MIL-STD-883 Method 2009.9 IPC-A-610 IPC-A-600 MIL-STD-883 Method 2008.4 JESD22A121 JESD201 IPC-TM-650 2.1.1 IPC-6012	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, includes NDE (Non-destructive Testing)	MIL-STD-883 Method 2012.7 J-STD-035 J-STD-020	Or customer specified test
Electrostatic discharge test. (Including: HBM / MM / CDM / Latch Up / ESD Gun )	JESD 47 JEDEC22-A114/A115/C101 EIA/JESD78 ANSI JEDEC ESDA JS001/JS002 AEC-Q100-002/003/004/011 AEC-Q101-001/002/005 AEC-Q200-002 JEITA ED4701 IEC61000-4-2 MIL-STD-883	Or customer specified test

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